

# **Dual Channel 12-Bit 500 Msps Analog to Digital Converter**

Check for Samples: ADS5407

# **FEATURES**

- Dual Channel
- 12-Bit Resolution
- Maximum Clock Rate: 500 Msps
- Low Swing Fullscale Input: 1.25 Vpp
- Analog Input Buffer with High Impedance Input
- Input Bandwidth (3dB): >1.0 GHz
- Data Output Interface: DDR LVDS
- Optional 2x Decimation with Low Pass or High Pass Filter
- 196-Pin BGA Package (12 x 12mm)

### **APPLICATIONS**

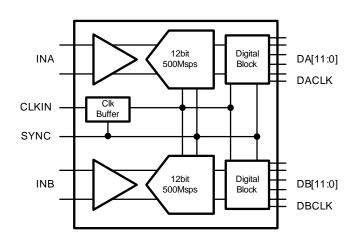
- Test and Measurement Instrumentation
- Ultra-Wide Band Software Defined Radio
- Data Acquisition
- Power Amplifier Linearization
- · Signal Intelligence and Jamming
- Radar and Satellite Systems
- Microwave Receivers

# **KEY SPECIFCATIONS**

- Power Dissipation: 675 mW/ch (Auto Correction Disabled)
- Spectral Performance at f<sub>IN</sub> = 230 MHz IF
  - SNR: 63.7 dBFS
  - SFDR:
    - 77 dBc (Auto Correction Disabled off)
    - 75 dBc (Auto Correction Disabled on)
- Spectral Performance at f<sub>IN</sub> = 450 MHz IF
  - SNR: 63.6 dBFS
  - SFDR:
    - 77 dBc (Auto Correction Disabled off)
    - 75 dBc (Auto Correction Disabled on)

### **DESCRIPTION**

The ADS5407 is a high linearity dual channel 12-bit, 500 MSPS analog-to-digital converter (ADC) easing front end filter design for wide bandwidth receivers. The analog input buffer isolates the internal switching of the onchip track-and-hold from disturbing the signal source as well as providing a high-impedance input. Optionally the output data can be decimated by two. Designed for high SFDR, the ADC has low-noise performance and outstanding spurious-free dynamic range over a large input-frequency range. The device is available in a 196 pin BGA package and is specified over the full industrial temperature range (–40°C to 85°C).



Device Part No.	Number of Channels	Speed Grade
ADS5402	2	800 Msps
ADS5401	1	800 Msps
ADS5404	2	500 Msps
ADS5403	1	500 Msps



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This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

# **DETAILED BLOCK DIAGRAM**

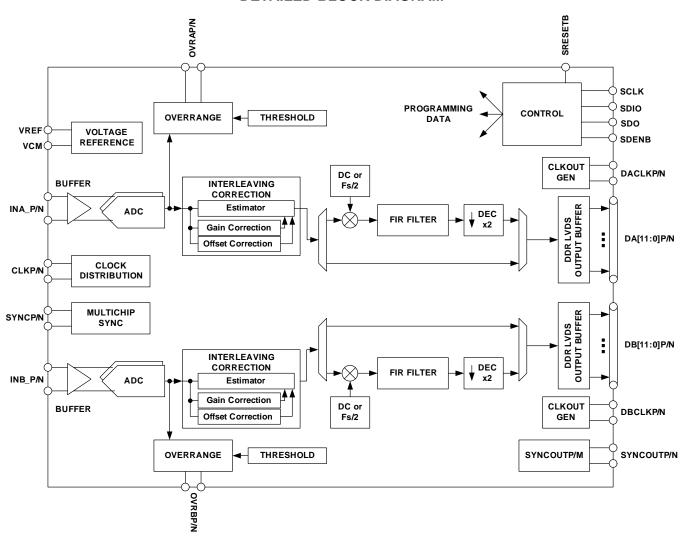


Figure 1. Detailed Block Diagram

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# **PINOUT INFORMATION**

	А	В	С	D	E	F	G	н	J	К	L	М	N	Р	
14	VREF	VCM	GND	INB_N	INB_P	GND	AVDDC	AVDDC	GND	INA_P	INA_N	GND	GND	CLKINP	14
13	SDENB	TEST MODE	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	CLKINN	13
12	SCLK	SRESET B	GND	AVDD33	AVDD33	AVDD33	AVDD33	AVDD33	AVDD33	AVDD33	AVDD33	GND	AVDD33	AVDD33	12
11	SDIO	ENABLE	GND	AVDD18	AVDD18	AVDD18	AVDD18	AVDD18	AVDD18	AVDD18	AVDD18	GND	AVDD18	AVDD18	11
10	SDO	IOVDD	GND	AVDD18	GND	GND	GND	GND	GND	GND	AVDD18	GND	NC	NC	10
9	DVDD	DVDD	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	SYNCN	SYNCP	9
8	DVDD	DVDD	DVDD	DVDD	GND	GND	GND	GND	GND	GND	DVDD	DVDD	DVDD	DVDD	8
7	DB0N	DB0P	DVDD LVDS	DVDD LVDS	GND	GND	GND	GND	GND	GND	DVDD LVDS	DVDD LVDS	NC	NC	7
6	DB1N	DB1P	DVDD LVDS	DVDD LVDS	GND	GND	GND	GND	GND	GND	DVDD LVDS	DVDD LVDS	NC	NC	6
5	DB2N	DB2P	OVRBN	OVRBP	GND	GND	GND	GND	GND	GND	OVRAN	OVRAP	SYNC OUTN	SYNC OUTP	5
4	DB3N	DB3P	DB8P	DB10P	NC	NC	NC	DA0P	DA2P	DA4P	DA6P	DA8P	NC	NC	4
3	DB4N	DB4P	DB8N	DB10N	NC	NC	NC	DAON	DA2N	DA4N	DA6N	DA8N	DA11N	DA11P	3
2	DB5N	DB5P	DB7P	DB9P	DB11P	SYNC OUTP	DBCLKP	DACLKP	DA1P	DA3P	DA5P	DA7P	DA10N	DA10P	2
1	DB6N	DB6P	DB7N	DB9N	DB11N	SYNC OUTN	DBCLKN	DACLKN	DA1N	DA3N	DA5N	DA7N	DA9N	DA9P	1
	А	В	С	D	E	F	G	Н	J	К	L	М	N	Р	

Figure 2. Pinout in DDR output mode (top down view)

# **PIN ASSIGNMENTS**

F	PIN	1/0	DECORPORTOR
NAME	NUMBER	I/O	DESCRIPTION
INPUT/REFEREN	ICE		
INA_P/N	K14, L14	I	Analog ADC A differential input signal.
INB_P/N	D14, E14	I	Analog ADC B differential input signal.
VCM	B14	0	Output of the analog input common mode (nominally 1.9V). A 0.1µF capacitor to AGND is recommended.
VREF	A14	0	Reference voltage output (2V nominal). A 0.1µF capacitor to AGND is recommended, but not required.
CLOCK/SYNC			
CLKINP/N	P14, P13	I	Differential input clock
SYNCP/N	P9, N9	ı	Synchronization input. Inactive if logic low. When clocked in a high state initially, this is used for resetting internal clocks and digital logic and starting the SYNCOUT signal. Internal $100\Omega$ termination.
CONTROL/SERI	AL		



# **PIN ASSIGNMENTS (continued)**

	PIN		
NAME	NUMBER	I/O	DESCRIPTION
SRESET	B12	I	Serial interface reset input. Active low. Initialized internal registers during high to low transition. Asynchronous. Internal $50k\Omega$ pull up resistor to IOVDD.
ENABLE	B11	I	Chip enable – active high. Power down function can be controlled through SPI register assignment. Internal $50k\Omega$ pull up resistor to IOVDD.
SCLK	A12	I	Serial interface clock. Internal 50kΩ pull-down resistor.
SDIO	A11	I/O	Bi-directional serial data in 3 pin mode (default). In 4-pin interface mode (register x00, D16), the SDIO pin is an input only. Internal $50k\Omega$ pull-down.
SDENB	A13	I	Serial interface enable. Internal 50kΩ pull-down resistor.
SDO	A10	0	Uni-directional serial interface data in 4 pin mode (register x00, D16). The SDO pin is tristated in 3-pin interface mode (default). Internal $50k\Omega$ pull-down resistor.
TESTMODE	B13	ı	Factory internal test, do not connect
DATA INTERFA	CE		
DA[11:0]P/N	P3, N3, P2, N2, P1, N1, M4, M3, M2, M1, L4, L3, L2, L1, K4, K3, K2, K1, J4, J3, J2, J1, H4, H3	0	ADC A Data Bits 11 (MSB) to 0 (LSB) in DDR output mode. Standard LVDS output.
DB[11:0]P/N	E2, E1, D4, D3, D2, D1, C4, C3, C2, C1, B1, A1, B2, A2, B3, A3, B4, A4, B5, A5, B6, A6, B7, A7	0	ADC B Data Bits 11 (MSB) to 0 (LSB) in DDR output mode. Standard LVDS output.
DACLKP/N	H2, H1	0	DDR differential output data clock for Bus A. Register programmable to provide either rising or falling edge to center of stable data nominal timing.
DBCLKP/N	G2, G1	0	DDR differential output data clock for Bus B. Register programmable to provide either rising or falling edge to center of stable data nominal timing. Optionally Bus B can be latched with DACLKP/N.
SYNCOUTP/N	F2, F1, P5, N5	0	Synchronization output signal for synchronizing multiple ADCs. Can be disabled via SPI.
OVRAP/N	M5, L5	0	Bus A, Overrange indicator, LVDS output. A logic high signals an analog input in excess of the full-scale range. Optional SYNC output.
OVRBP/N	D5, C5	0	Bus B, Overrange indicator, LVDS output. A logic high signals an analog input in excess of the full-scale range. Optional SYNC output.
NC	E3, E4, F3, F4, G3, G4, N4, N6, N7, N10, P4, P6, P7, P10	_	Don't connect to pin
POWER SUPPL	Υ		
AVDD33	D12, E12, F12, G12, H12, J12, K12, L12, N12, P12	I	3.3V analog supply
AVDDC	G14, H14	I	1.8V supply for clock input
AVDD18	D10, D11, E11, F11, G11, H11, J11, K11, L10, L11, N11, P11	I	1.8V analog supply
DVDD	A8, A9, B8, B9, C8, D8, L8, M8, N8, P8	I	1.8V supply for digital block
DVDDLVDS	C6, C7, D6, D7, L6, L7, M6, M7	I	1.8V supply for LVDS outputs
IOVDD	B10	I	1.8V for digital I/Os
GND		I	Ground

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### **PACKAGE/ORDERING INFORMATION**

PRODUCT	PACKAGE- LEAD	PACKAGE DESIGNATOR	SPECIFIED TEMPERATURE RANGE	PACKAGE MARKING	ORDERING NUMBER	TRANSPORT MEDIA, QUANTITY
AD05407	100 DCA	74.	400 4- 050	AD054071	ADS5407IZAY	Tray
ADS5407	196-BGA	ZAY	-40C to 85C	ADS5407I	ADS5407IZAYR	Tape and Reel

# **ABSOLUTE MAXIMUM RATINGS**

over operating free-air temperature range (unless otherwise noted)

		VA	ALUE	UNIT	
		MIN	MIN MAX		
Supply voltage range, AVDD3	3	-0.5	4	V	
Supply voltage range, AVDDC	-0.5	2.3	V		
Supply voltage range, AVDD1	-0.5	2.3	V		
Supply voltage range, DVDD	-0.5	2.3	V		
Supply voltage range, DVDDL	-0.5	-0.5 2.3			
Supply voltage range, IOVDD		-0.5	4	V	
	INA/B_P, INA/B_N	-0.5	AVDD33 + 0.5	V	
Valtage applied to input pine	CLKINP, CLKINN	-0.5	AVDDC + 0.5	V	
Voltage applied to input pins	SYNCP, SYNCN	-0.5	AVDD33 + 0.5	V	
	SRESET, SDENB, SCLK, SDIO, SDO, ENABLE	-0.5	IOVDD + 0.5	V	
Operating free-air temperature	e range, T <sub>A</sub>	-40	85	°C	
Operating junction temperatur		150	°C		
Storage temperature range	-65	150	°C		
ESD, Human Body Model		2	kV		

# THERMAL INFORMATION

	TUEDMAL METDIO(1)	ADS5407	LINUTO
	THERMAL METRIC <sup>(1)</sup>	QFN (196-PIN)	UNITS
$\theta_{JA}$	Junction-to-ambient thermal resistance	37.6	
$\theta_{JCtop}$	Junction-to-case (top) thermal resistance	6.8	
$\theta_{JB}$	Junction-to-board thermal resistance	16.8	°C/W
Ψлт	Junction-to-top characterization parameter	0.2	
ΨЈВ	Junction-to-board characterization parameter	16.4	

<sup>(1)</sup> For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.

# RECOMMENDED OPERATING CONDITIONS

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT		
_	Recommended operating junction temperature			105	۰۰		
IJ	Maximum rated operating junction temperature <sup>(1)</sup>	125			°C		
T <sub>A</sub>	Recommended free-air temperature	-40	25	85	°C		

(1) Prolonged use at this junction temperature may increase the device failure-in-time (FIT) rate.



Typical values at  $T_A = 25^{\circ}\text{C}$ , full temperature range is  $T_{\text{MIN}} = -40^{\circ}\text{C}$  to  $T_{\text{MAX}} = 85^{\circ}\text{C}$ , ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input (unless otherwise noted).

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
ADC Clock	Frequency		40		500	MSPS
Resolution	1		12			Bits
SUPPLY		•	•		•	
AVDD33			3.15	3.3	3.45	V
AVDDC, A	VDD18, DVDD, DVDDLVDS		1.7	1.8	1.9	V
IOVDD			1.7	1.8	3.45	V
POWER S	UPPLY					
I <sub>AVDD33</sub>	3.3V Analog supply current			239	270	mA
I <sub>AVDD18</sub>	1.8V Analog supply current			79	90	mA
I <sub>AVDDC</sub>	1.8V Clock supply current			27	35	mA
I <sub>DVDD</sub>	1.8V Digital supply current	Auto Correction Disabled		117	140	mA
I <sub>DVDD</sub>	1.8V Digital supply current	Auto Correction Enabled		207		mA
I <sub>DVDD</sub>	1.8V Digital supply current	Auto Correction Disabled, decimation filter enabled		142		mA
I <sub>DVDDLVDS</sub>	1.8V LVDS supply current	Unused LVDS outputs Disabled		104	120	mA
I <sub>IOVDD</sub>	1.8V I/O Voltage supply current			1	2	mA
P <sub>dis</sub>	Total power dissipation	Auto Correction Disabled, decimation filter disabled		1.35	1.5	W
PSRR		250kHz to 500MHz	40			dB
Shut-down	power dissipation			7		mW
Shut-down	wake up time			2.5		ms
Standby po	wer dissipation			7		mW
Standby wa	ake up time			100		μs
Dana alaan	and a manuar discination	Auto correction disabled		264		mW
Deep-sleep mode power dissipation		Auto correction enabled		371		mW
Deep-sleep mode wakeup time				20		μs
: =   =   =	and a name discipation	Auto correction disabled		559		mW
Light-sieep	mode power dissipation	Auto correction enabled		666		mW
Light-sleep	mode wakeup time			2		μs

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Typical values at  $T_A = 25^{\circ}\text{C}$ , full temperature range is  $T_{MIN} = -40^{\circ}\text{C}$  to  $T_{MAX} = 85^{\circ}\text{C}$ , ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD3V = 3.3V, AVDD/DRVDD/IOVDD = 1.8V, -1dBFS differential input (unless otherwise noted).

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
ANALOG INPUTS		1			
Differential input full-scale			1.0	1.25	Vpp
Input common mode voltage			1.9	±0.1	V
Input resistance	Differential at DC		1		kΩ
Input capacitance	Each input to GND		2		pF
VCM common mode voltage output			1.9		V
Analog input bandwidth (3dB)			1000		MHz
DYNAMIC ACCURACY					
Offset Error	Auto Correction Disabled	-20	±4	20	mV
	Auto Correction Enabled	-1	0	1	mV
Offset temperature coefficient			-611		μV/°C
Gain error		<b>–</b> 5	±0.6	5	%FS
Gain temperature coefficient			0.005		%FS/°C
Differential nonlinearity	f <sub>IN</sub> = 230 MHz	-1	±0.8	2	LSB
Integral nonlinearity	f <sub>IN</sub> = 230 MHz	<b>–</b> 5	±2	5	LSB
CLOCK INPUT					
Input clock frequency		40		500	MHz
Input clock amplitude			2		Vpp
Input clock duty cycle		40%	50%	60%	
Internal clock biasing			0.9		V



Typical values at  $T_A = 25^{\circ}\text{C}$ , full temperature range is  $T_{\text{MIN}} = -40^{\circ}\text{C}$  to  $T_{\text{MAX}} = 85^{\circ}\text{C}$ , ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input (unless otherwise noted).

	PARAMETER	TEST CONDITIONS	MIN TYP MA	X MIN	TYP	MAX	UNITS
Auto Co			Enabled		Disabled		Vpp
DYNAMI	C AC CHARACTERISTICS <sup>(1)</sup> -	Vref = 1.25V					
		f <sub>IN</sub> = 10 MHz	63.6		63.8		
		f <sub>IN</sub> = 100 MHz	63.5		63.7		
SNR	Signal to Noise Ratio	f <sub>IN</sub> = 230 MHz	63.5	61.5	63.7		dBFS
		f <sub>IN</sub> = 450 MHz	63.1		63.6		
		f <sub>IN</sub> = 700 MHz	62.5		63.2		
		f <sub>IN</sub> = 10 MHz	84		81		
		f <sub>IN</sub> = 100 MHz	84		83		
HD2,3	Second and third harmonic distortion	f <sub>IN</sub> = 230 MHz	76	55	77		dBc
	distortion	f <sub>IN</sub> = 450 MHz	82		84		
		f <sub>IN</sub> = 700 MHz	74		74		
		f <sub>IN</sub> = 10 MHz	78		79		
	Spur Free Dynamic Range	f <sub>IN</sub> = 100 MHz	78		79		
Non HD2,3	(excluding second, third harmonic distortion and Fs/2-	f <sub>IN</sub> = 230 MHz	76	70	77		dBc
1102,0	Fin spur)  Fs/2-Fin interleaving spur	f <sub>IN</sub> = 450 MHz	76		77		
		f <sub>IN</sub> = 700 MHz	72		72		
		f <sub>IN</sub> = 10 MHz	90		87		
		f <sub>IN</sub> = 100 MHz	86		85		dBc
IL		f <sub>IN</sub> = 230 MHz	83	60	80		
		f <sub>IN</sub> = 450 MHz	81		80		
		f <sub>IN</sub> = 700 MHz	77		77		
		f <sub>IN</sub> = 10 MHz	63.4		63.6		
		f <sub>IN</sub> = 100 MHz	63.3		63.5		
SINAD	Signal to noise and distortion ratio	f <sub>IN</sub> = 230 MHz	63.1	55	63.4		dBFS
	rano	f <sub>IN</sub> = 450 MHz	62.8		63.0		
		f <sub>IN</sub> = 700 MHz	61.8		62.4		
		f <sub>IN</sub> = 10 MHz	77		77		
		f <sub>IN</sub> = 100 MHz	76		77		
THD	Total Harmonic Distortion	f <sub>IN</sub> = 230 MHz	74	54	74		dBc
		f <sub>IN</sub> = 450 MHz	75		75		
		f <sub>IN</sub> = 700 MHz	70		70		
IMDs	Inter modulation distortion	f <sub>IN</sub> = 129.5 and 130.5MHz, -7dBFS	83		83		4DE0
IMD3	Inter modulation distortion	f <sub>IN</sub> = 349.5 and 350.5MHz, -7dBFS	80		78		dBFS
	Crosstalk		90		90		dB
ENOB	Effective number of bits	f <sub>IN</sub> = 230 MHz	10.2		10.3		Bit

<sup>(1)</sup> SNR calculations do not include the DC, Fs/2 and Fs/2-fin bins when Auto correction is disabled.



Typical values at  $T_A = 25^{\circ}$ C, full temperature range is  $T_{MIN} = -40^{\circ}$ C to  $T_{MAX} = 85^{\circ}$ C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input (unless otherwise noted).

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
OVER	-DRIVE RECOVERY ERROF	8				
	Input overload recovery	Recovery to within 5% (of final value) for 6dB overload with sine wave input		2		ns
SAMP	LE TIMING CHARACTERIS	TICS				
rms	Aperture Jitter	Sample uncertainty		100		fs rms
		ADC sample to digital output, auto correction disabled		38		Clock
		ADC sample to digital output, auto correction enabled		50		Cycles
	Data Latency	ADC sample to digital output, Decimation filter enabled, Auto correction disabled		74		Sampling clock Cycles
	Over-range Latency	ADC sample to over-range output		12		Clock Cycles

# **ELECTRICAL CHARACTERISTICS**

The DC specifications refer to the condition where the digital outputs are not switching, but are permanently at a valid logic level 0 or 1. AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
DIGITA	L INPUTS – SRESET, SCLK, SDE	NB, SDIO, ENABLE			Ų.	
	High-level input voltage	All digital inputs support 1.8V and 3.3V logic	0.7 x IOVDD			V
	Low-level input voltage	levels.			0.3 x IOVDD	V
	High-level input current		-50		200	μΑ
	Low-level input current		-50		50	μΑ
	Input capacitance			5		pF
DIGITA	L OUTPUTS – SDO					
	High-level output voltage	I <sub>Load</sub> = -100uA	IOVDD – 0.2			V
	nign-ievei output voitage	I <sub>Load</sub> = -2mA	0.8 x IOVDD			V
		I <sub>Load</sub> = 100uA			0.2	
	Low-level output voltage	I <sub>Load</sub> = 2mA			0.22 x IOVDD	V
DIGITA	L INPUTS – SYNCP/N, TRIGGERF	P/N				
$V_{ID}$	Differential input voltage		250	350	450	mV
$V_{\text{CM}}$	Input common mode voltage		1.125	1.2	1.375	V
$t_{SU}$			500			ps
DIGITA	L OUTPUTS – DA[11:0]P/N, DACI	_KP/N, OVRAP/N, SYNCOUTP/N, TRDYP/N, HF	RESP/N, DB[11:0	D]P/N, DBC	LKP/N, O\	/RBP/N,
$V_{OD}$	Output differential voltage	$I_{OUT} = 3.5 \text{mA}$	250	350	450	mV
$V_{\text{OCM}}$	Output common mode voltage	$I_{OUT} = 3.5 \text{mA}$	1.125	1.25	1.375	V
$t_{suA}$	$F_s = 500Msps$	Data valid to zero-crossing of DACLK	600	800		ps
t <sub>hA</sub>	F <sub>s</sub> = 500Msps	Zero-crossing of DACLK to data becoming invalid	600	790		ps
t <sub>suB</sub>	F <sub>s</sub> = 500Msps	Data valid to zero-crossing of DBCLK	700	900		ps
t <sub>hB</sub>	F <sub>s</sub> = 500Msps	Zero-crossing of DBCLK to data becoming invalid	500	600		ps
t <sub>PD</sub>	F <sub>s</sub> = 500Msps	CLKIN falling edge to DACLK, DBCLK rising edge	3.28	3.48	3.74	ns



The DC specifications refer to the condition where the digital outputs are not switching, but are permanently at a valid logic level 0 or 1. AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
t <sub>RISE</sub>	10% - 90%	100	150	200	ps
t <sub>FALL</sub>	90% - 10%	100	150	200	ps

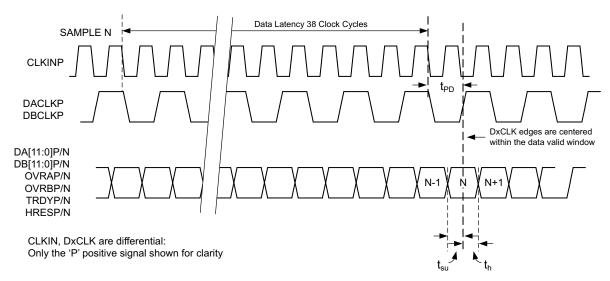
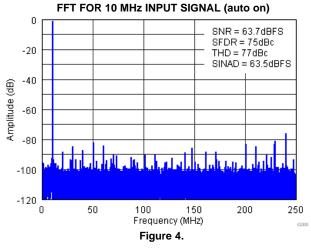


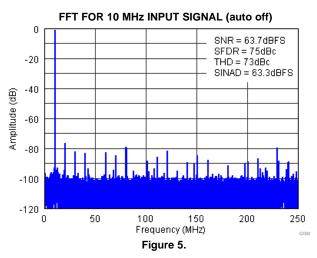
Figure 3. Timing Diagram for 12-bit DDR Output

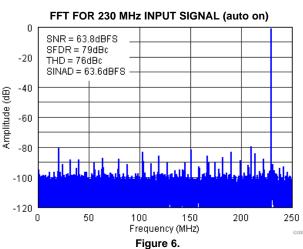


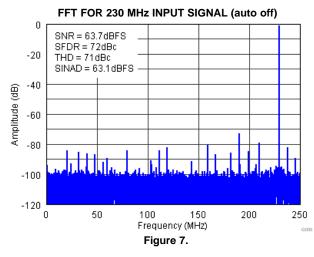
### TYPICAL CHARACTERISTICS

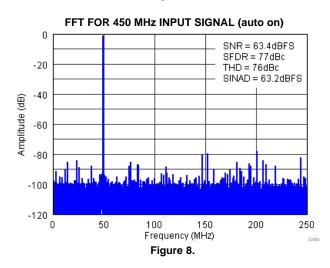
Typical values at TA = +25°C, full temperature range is  $T_{MIN}$  = -40°C to  $T_{MAX}$  = +85°C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, Vref = 1.25V, -1dBFS differential input, unless otherwise noted.

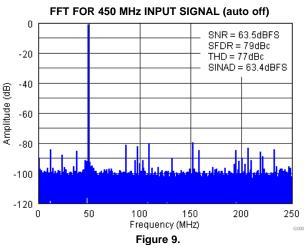






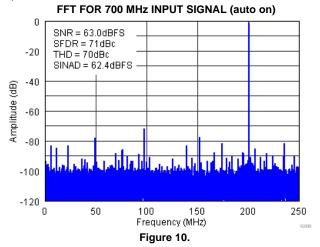


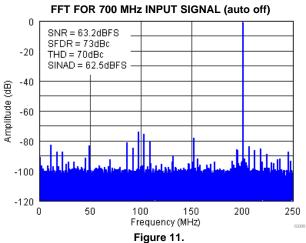


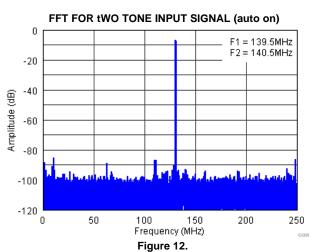


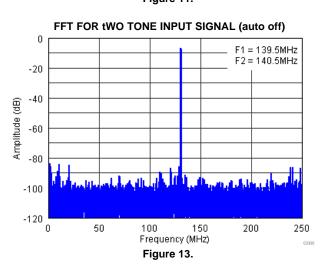


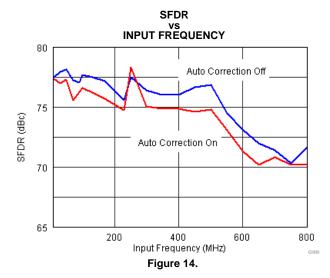
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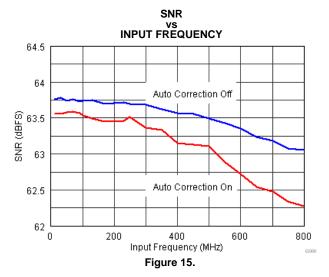










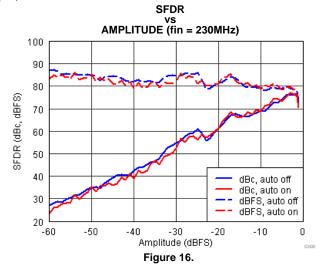


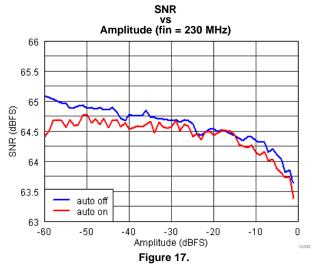
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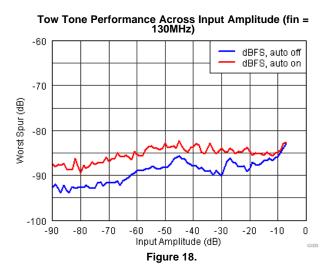
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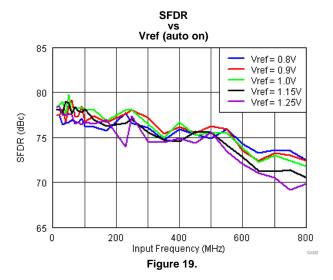


Typical values at TA = +25°C, full temperature range is  $T_{MIN}$  = -40°C to  $T_{MAX}$  = +85°C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, Vref = 1.25V, -1dBFS differential input, unless otherwise noted.







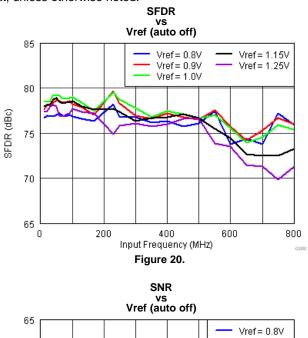


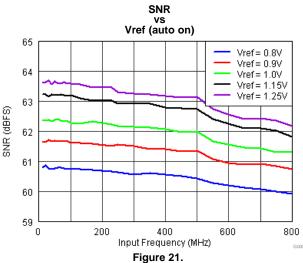
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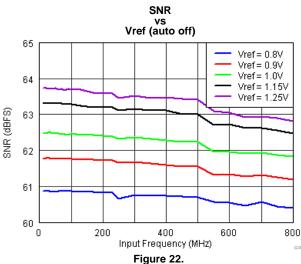
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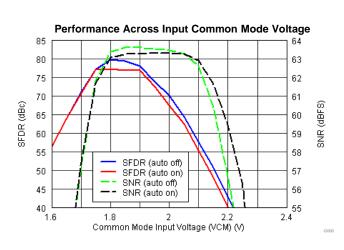


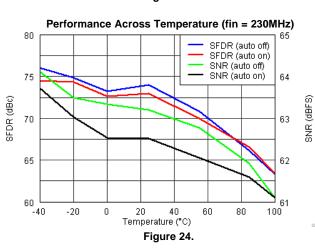
Typical values at TA = +25°C, full temperature range is  $T_{MIN}$  = -40°C to  $T_{MAX}$  = +85°C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, Vref = 1.25V, -1dBFS differential input, unless otherwise noted.

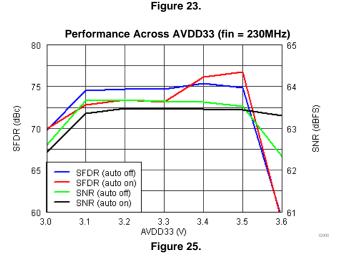










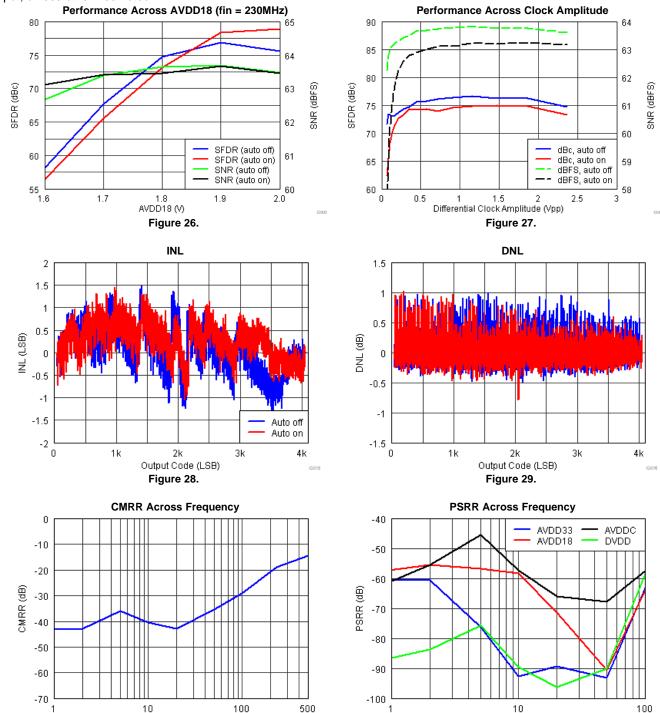


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Typical values at TA = +25°C, full temperature range is  $T_{MIN}$  = -40°C to  $T_{MAX}$  = +85°C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, Vref = 1.25V, -1dBFS differential input, unless otherwise noted.



Product Folder Links: ADS5407

Frequency (MHz)

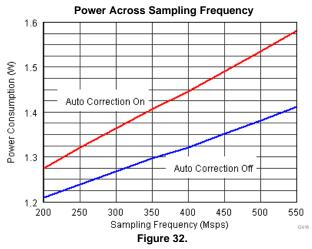
Figure 31.

Frequency Of common mode signal (MHz)

Figure 30.



Typical values at TA = +25°C, full temperature range is  $T_{MIN}$  = -40°C to  $T_{MAX}$  = +85°C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, Vref = 1.25V, -1dBFS differential input, unless otherwise noted.



### SFDR Across Input and Sampling Frequencies (auto on)

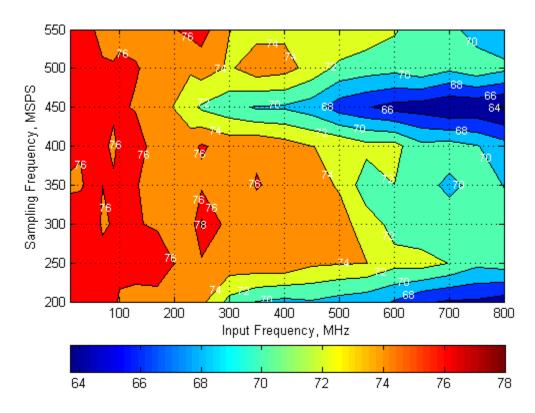


Figure 33.



Typical values at TA = +25°C, full temperature range is  $T_{MIN}$  = -40°C to  $T_{MAX}$  = +85°C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, Vref = 1.25V, -1dBFS differential input, unless otherwise noted.

# SFDR Across Input and Sampling Frequencies (auto off)

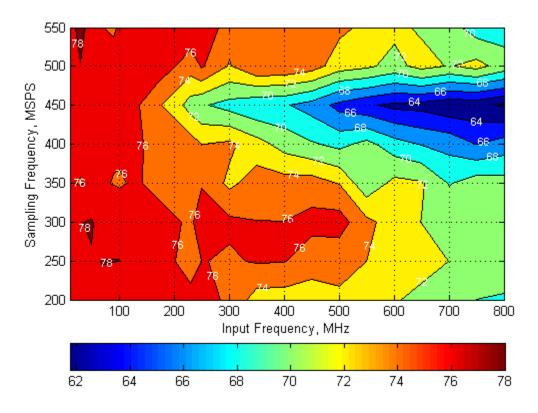


Figure 34.



Typical values at TA = +25°C, full temperature range is  $T_{MIN}$  = -40°C to  $T_{MAX}$  = +85°C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, Vref = 1.25V, -1dBFS differential input, unless otherwise noted.

# SNR Across Input and Sampling Frequencies (auto on)

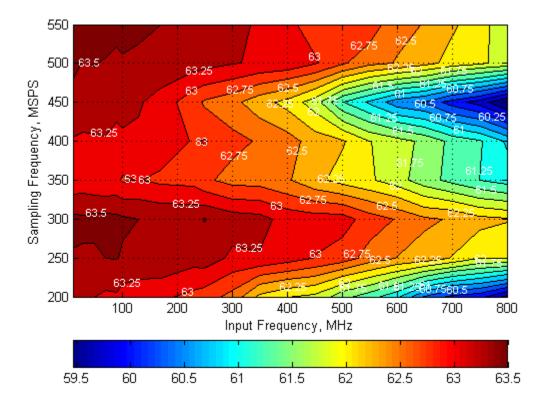


Figure 35.

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Typical values at TA = +25°C, full temperature range is  $T_{MIN}$  = -40°C to  $T_{MAX}$  = +85°C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, Vref = 1.25V, -1dBFS differential input, unless otherwise noted.

# SNR Across Input and Sampling Frequencies (auto on)

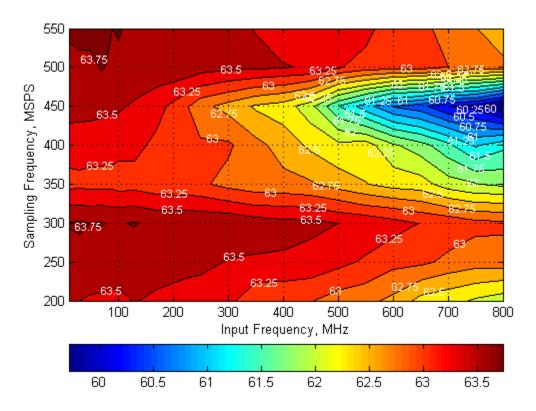


Figure 36.



### **FEATURES**

### **POWER DOWN MODES**

The ADS5407 can be configured via SPI write (address x37) to a stand-by, light or deep sleep power mode which is controlled by the ENABLE pin. The sleep modes are active when the ENABLE pin goes low. Different internal functions stay powered up which results in different power consumption and wake up time between the two sleep modes.

Sleep mode	Wake up time	Power Consumption Auto Correction Disabled	Power Consumption Auto Correction Enabled
Complete Shut Down	2.5 ms	7mW	7mW
Stand-by	100µs	7mW	7mW
Deep Sleep	20µs	264mW	371mW
Light Sleep	2μs	559mW	666mW

# **TEST PATTERN OUTPUT**

The ADS5407 can be configured to output different test patterns that can be used to verify the digital interface is connected and working properly.

To enable the test pattern mode, the high performance mode 1 has to be disabled first via SPI register write. Then different test patterns can be selected by configuring registers x3C, x3D and x3E. All three registers must be configured for the test pattern to work properly.

First set HP1 = 0 (Addr 0x01, D01)

Register Address	All 0s	All 1s	Toggle (0xAAA => 0x555)	Toggle (0xFFF => 0x000)
0x3C	0x8000	0xBFFC	0x9554	0xBFFC
0x3D	0x0000	0x3FFC	0x2AA8	0x0000
0x3E	0x0000	0x3FFC	0x1554	0x3FFC

Register Address							ı	Custom	Patterr	1						
	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
x3C	1	0													0	0
x3D	0	0	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0	0	0
x3E	0	0													0	0

For normal operation, set HP1 = 1 (Addr 0x01, D01) and 0x3C, 0x3D, 0x3E all to 0.

# **CLOCK INPUT**

The ADS5407 clock input can be driven differentially with a sine wave, LVPECL or LVDS source with little or no difference in performance. The common mode voltage of the clock input is set to 0.9V using internal  $2k\Omega$  resistors. This allows for AC coupling of the clock inputs. The termination resistors should be placed as close as possible to the clock inputs in order to minimize signal reflections and jitter degradation.

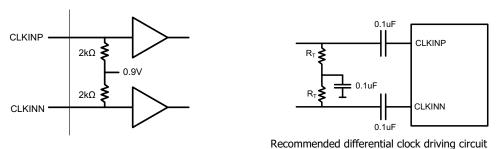


Figure 37. Recommended Differential Clock Driving Circuit



### **SNR AND CLOCK JITTER**

The signal to noise ratio of the ADC is limited by three different factors: the quantization noise is typically not noticeable in pipeline converters and is 74dB for a 12bit ADC. The thermal noise limits the SNR at low input frequencies while the clock jitter sets the SNR for higher input frequencies.

$$SNR_{ADC}[dBc] = -20 \times log \sqrt{10 - \frac{SNR_{Quantization\_Noise}}{20}}^2 + \left(10 - \frac{SNR_{ThermalNoise}}{20}\right)^2 + \left(10 - \frac{SNR_{Jitter}}{20}\right)^2}$$
(1)

The SNR limitation due to sample clock jitter can be calculated as following:

$$SNR_{Jitter} [dBc] = -20 \times log(2\pi \times f_{IN} \times t_{Jitter})$$
(2)

The total clock jitter (TJitter) has three components – the internal aperture jitter (100fs for ADS5407) which is set by the noise of the clock input buffer, the external clock jitter and the jitter from the analog input signal. It can be calculated as following:

$$T_{\text{Jitter}} = \sqrt{\left(T_{\text{Jitter,Ext.Clock\_Input}}\right)^2 + \left(T_{\text{Aperture\_ADC}}\right)^2}$$
(3)

External clock jitter can be minimized by using high quality clock sources and jitter cleaners as well as bandpass filters at the clock input while a faster clock slew rate improves the ADC aperture jitter.

The ADS5407 has a thermal noise of 63.8 dBFS and internal aperture jitter of 100fs. The SNR depending on amount of external jitter for different input frequencies is shown in the following figure.

# SNR vs Input Frequency and External Clock Jitter 64.0 63.0 63.0 62.0 35 fs 50 fs 100 fs 150 fs 200 fs 100 100 100 1000

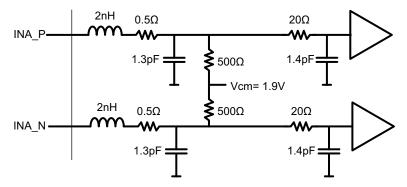
Fin (MHz)



### **ANALOG INPUTS**

The ADS5407 analog signal inputs are designed to be driven differentially. The analog input pins have internal analog buffers that drive the sampling circuit. As a result of the analog buffer, the input pins present a high impedance input across a very wide frequency range to the external driving source which enables great flexibility in the external analog filter design as well as excellent  $50\Omega$  matching for RF applications. The buffer also helps to isolate the external driving circuit from the internal switching currents of the sampling circuit which results in a more constant SFDR performance across input frequencies.

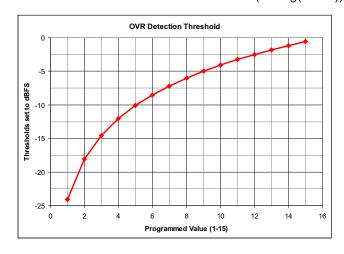
The common-mode voltage of the signal inputs is internally biased to 1.9V using  $500\Omega$  resistors which allows for AC coupling of the input drive network. Each input pin (INP, INM) must swing symmetrically between (VCM + 0.25V) and (VCM - 0.25V), resulting in a 1.0Vpp (default) differential input swing. The input sampling circuit has a 3dB bandwidth that extends up to 1.2GHz.



### **OVER-RANGE INDICATION**

The ADS5407 provides a fast over-range indication on the OVRA/B pins. The fast OVR is triggered if the input voltage exceeds the programmable overrange threshold and it gets presented after just 12 clock cycles enabling a quicker reaction to an overrange event. The OVR threshold can be configured using SPI register writes.

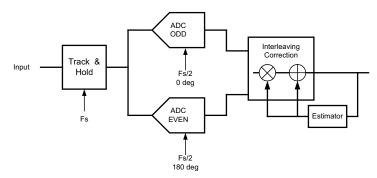
The input voltage level at which the overload is detected is referred to as the threshold and is programmable using the Over-range threshold bits. The threshold at which fast OVR is triggered is (full-scale × [the decimal value of the FAST OVR THRESH bits] /16). After reset, the default value of the over-range threshold is set to 15 (decimal) which corresponds to a threshold of 0.56dB below full scale (20\*log(15/16)).





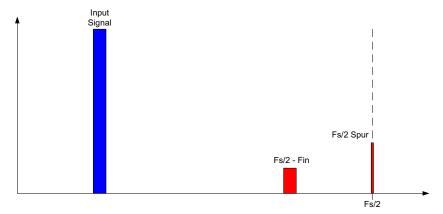
### INTERLEAVING CORRECTION

Each of the two data converter channels consists of two interleaved ADCs each operating at half of the ADC sampling rate but 180° out of phase from each other. The front end track and hold circuitry is operating at the full ADC sampling rate which minimizes the timing mismatch between the two interleaved ADCs. In addition the ADS5407 is equipped with internal interleaving correction logic that can be enabled via SPI register write.



The interleaving operation creates 2 distinct and interleaving products:

- Fs/2 Fin: this spur is created by gain timing mismatch between the ADCs. Since internally the front end track and hold is operated at the full sampling rate, this component is greatly improved and mostly dependent on gain mismatch.
- Fs/2 Spur: due to offset mismatch between ADCs



The auto correction loop can be enabled via SPI register write in address 0x01 and resetting the correction circuit in address 0x03 and 0x1A. By default, it is disabled for lowest possible power consumption. The DC correction function can be enabled in 0x03 & 0x1A for chA and chB respectively. The default settings for the auto correction function should work for most applications. However please contact Texas Instruments if further fine tuning of the algorithm is required.

The auto correction function yields best performance for input frequencies below 250MHz. For input frequencies greater than 250MHz it is recommended to disable the auto gain correction loop.



### **DECIMATION FILTER**

Each channel has a digital filter in the data path as shown in Figure 38. The filter can be programmed as a low-pass or a high-pass filter and the normalized frequency response of both filters is shown in Figure 39.

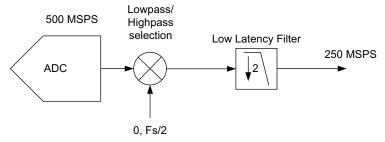


Figure 38.

The decimation filter response has a 0.1dB pass band ripple with approximately 41% pass-band bandwidth. The stop-band attenuation is approximately 40dB.

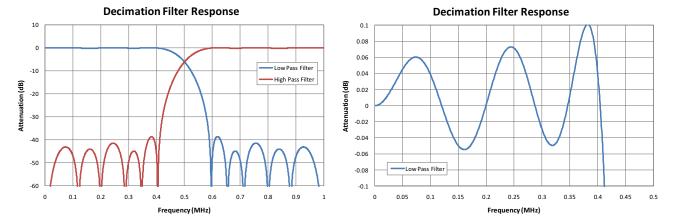
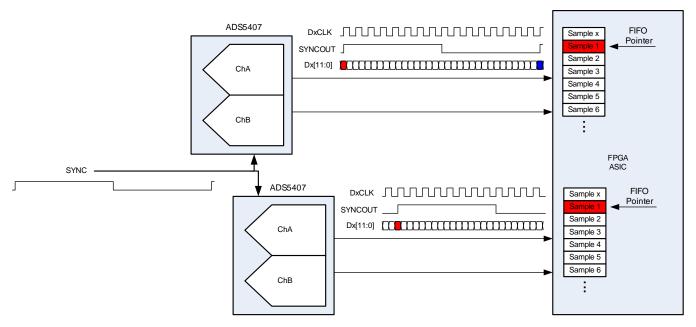


Figure 39.



### **MULTI DEVICE SYNCHRONIZATION**

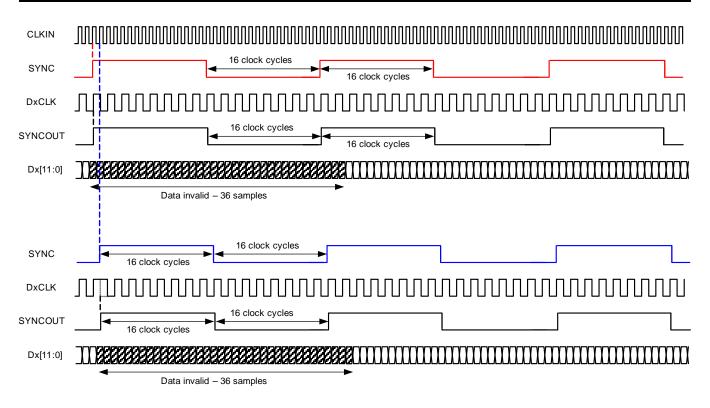
The ADS5407 simplifies the synchronization of data from multiple ADCs in one common receiver. Upon receiving the initial SYNC input signal, the ADS5407 resets all the internal clocks and digital logic while also starting a SYNCOUT signal which operates on a 5bit counter (32 clock cycles). Therefore by providing a common SYNC signal to multiple ADCs their output data can be synchronized as the SYNCOUT signal marks a specific sample with the same latency in all ADCs. The SYNCOUT signal then can be used in the receiving device to synchronize the FIFO pointers across the different input data streams. Thus the output data of multiple ADCs can be aligned properly even if there are different trace lengths between the different ADCs.



The SYNC input signal should be a periodic signal repeating every 32 CLKIN clock cycles. It gets registered on the rising edge of the ADC input clock (CLKIN). Upon registering the initial rising edge of the SYNC signal, the internal clocks and logic get reset which results in invalid output data for 36 samples (1 complete sync cycle and 4 additional samples). The SYNCOUT signal starts with the next output clock (DACLK) rising edge and operates on a 5-bit counter independent from the SYNC signal frequency and duty cycle.

Since the ADS5407 output interface operates with a DDR clock, the synchronization can happen on the rising edge or falling edge sample. Synchronization on the falling edge sample will result in a half cycle clock stretch of DA/BCLK. For convenience the SYNCOUT signal is available on the ChA/B output LVDS bus. When using decimation the SYNCOUT signal still operates on 32 clock cycles of CLKIN but since the output data is decimated by 2, only the first 18 samples should be discarded.







### PROGRAMMING INTERFACE

The serial interface (SIF) included in the ADS5407 is a simple 3 or 4 pin interface. In normal mode, 3 pins are used to communicate with the device. There is an enable (SDENB), a clock (SCLK) and a bi-directional IO port (SDIO). If the user would like to use the 4 pin interface one write must be implemented in the 3 pin mode to enable 4 pin communications. In this mode, the SDO pin becomes the dedicated output. The serial interface has an 8-bit address word and a 16-bit data word. The first rising edge of SCLK after SDENB goes low will latch the read/write bit. If a high is registered then a read is requested, if it is low then a write is requested. SDENB must be brought high again before another transfer can be requested. The signal diagram is shown below:

### **Register Initialization**

After power up, the internal registers must be initialized to the default values. This initialization can be accomplished in one of two ways:

- 1. Either through hardware reset by applying a low pulse on SRESET pin
- 2. By applying a software reset. When using the serial interface, a reset can be performed by addressing register x2C. This setting initializes the internal registers to the default values and then self-resets the RESET register to 0. In this case the SRESET pin can be kept high.

### **Serial Register Write**

The internal register of the ADS5407 can be programmed following these steps:

- 1. Drive SDENB pin low
- 2. Set the R/W bit to '0' (bit A7 of the 8 bit address)
- 3. Initiate a serial interface cycle specifying the address of the register (A6 to A0) whose content has to be written
- 4. Write 16bit data which is latched on the rising edge of SCLK

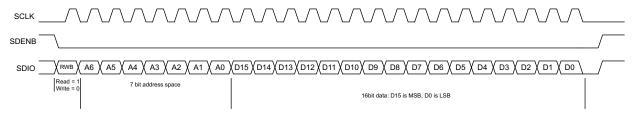


Figure 40. Serial Register Write Timing Diagram

	PARAMETER	MIN	TYP <sup>(1)</sup>	MAX	UNIT
f <sub>SCLK</sub>	SCLK frequency (equal to 1/tSCLK)	>DC		20	MHz
t <sub>SLOADS</sub>	SDENB to SCLK setup time	25			ns
t <sub>SLOADH</sub>	SCLK to SDENB hold time	25			ns
t <sub>DSU</sub>	SDIO setup time	25			ns
t <sub>DH</sub>	SDIO hold time	25			ns

(1) Typical values at +25°C; minimum and maximum values across the full temperature range: TMIN = -40°C to TMAX = +85°C, AVDD3V = 3.3V, AVDD, DRVDD = 1.9V, unless otherwise noted.



# **Serial Register Readout**

The device includes a mode where the contents of the internal registers can be read back using the SDO/SDIO pins. This read-back mode may be useful as a diagnostic check to verify the serial interface communication between the external controller and the ADC.

- 1. Drive SDENB pin low
- 2. Set the RW bit (A7) to '1'. This setting disables any further writes to the registers
- 3. Initiate a serial interface cycle specifying the address of the register (A6 to A0) whose content has to be read.
- 4. The device outputs the contents (D15 to D0) of the selected register on the SDO/SDIO pin
- 5. The external controller can latch the contents at the SCLK rising edge.
- 6. To enable register writes, reset the RW register bit to '0'.

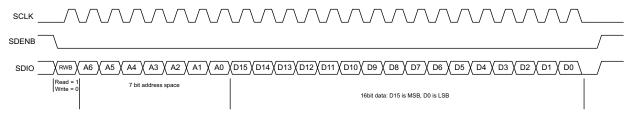


Figure 41. Serial Register Read Timing Diagram

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Product Folder Links: ADS5407



# SERIAL REGISTER MAP(2)

(2) Multiple functions in a register can be programmed in a single write operation.

Register Address								Regist	er Data							
A7-A0 IN HEX	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
0	3/4 Wire SPI	Decimat ion Filter EN	0	ChA High/ Low Pass	0	0	ChB High/ Low Pass	0	0	0	0	0	0	0	0	0
1	ChA Corr EN	0	0	0	0	0	ChB Corr EN	0	0	0	0	0	Data Format	0	Hp Mode1	0
2	0	0	0	0	0		Over-range	threshold		0	0	0	0	0	0	0
3	0	Start Auto Corr ChA	0	0	1	0	1	1	0	0	0	1	1	0	0	0
Е	Sync Select															
F		Sync	Select		0	0	0	0	0		VREF Set		0	0	0	0
1A	0	Start Auto Corr ChB	0	0	1	0	1	1	0	0	0	1	1	0	0	0
2B	0	0	0	0	0	0	0				Т	emp Sens	or			
2C				•				Re	set							
37			Sleep	Modes			0	0	0	0	0	0	0	0	0	0
38					HP Mode2	2	1			BIAS EN	SYNC EN	LP Mode 1	0	0	0	0
ЗА	LVDS	Current Sti	rength	LVD	S SW		al LVDS ination	0	0	0	0	DACLK EN	DBCLK EN	0	OVRA EN	OVRB EN
66				•		•	L	VDS Outp	ut Bus A E	N	•		•			
67							L	VDS Outp	ut Bus B E	N						

# **DESCRIPTION OF SERIAL INTERFACE REGISTERS**

Register Address								Regis	ter Data	a						
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
0	3/4 Wire SPI	Deci matio n Filter EN	0	ChA High/ Low Pass	0	0	ChB High/ Low Pass	0	0	0	0	0	0	Or	0	0

D15 3/4 Wire SPI Enables 4-bit serial interface when set

Default 0

0 3 wire SPI is used with SDIO pin operating as bi-directional I/O port

1 4 wire SPI is used with SDIO pin operating as data input and SDO pin as data output port.

D14 **Decimation** 2x decimation filter is enabled when bit is set

Filter EN

Default 0

0 Normal operation with data output at full sampling rate

1 2x decimation filter enabled

D12 ChA High/Low (Decimation filter must be enabled first: set bit D14)

**Pass** 

Default 0

0 Low Pass



1 High Pass

D9 ChB High/Low (Decimation filter must be enabled first: set bit D14)

**Pass** 

Default 0

0 Low Pass

1 High Pass

Register Address								Regis	ster Dat	a						
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
1	ChA Corr EN	0	0	0	0	0	ChB Corr EN	0	0	0	0	0	Data Format	0	HP Mode1	0

# D15 ChA Corr EN (should be enabled for maximum performance)

Default 0

- 0 auto correction disabled
- 1 auto correction enabled

# D9 ChB Corr EN (should be enabled for maximum performance)

Default 0

- 0 auto correction disabled
- 1 auto correction enabled

### D3 Data Format

Default 0

- 0 Two's complement
- 1 Offset Binary

# D1 HP Mode 1

Default 0

1 Must be set to 1 for optimum performance

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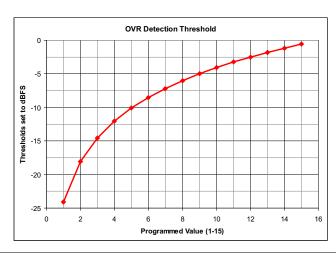
Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
2	0	0	0	0	0	Over-range threshold				0	0	0	0	0	0	0

# D10-D7 Over-range threshold

The over-range detection is triggered 20 output clock cycles after the overload condition occurs. The threshold at which the OVR is triggered =  $1.1V \times [\text{decimal value of } < \text{Over-range threshold} >]/16$ . After power up or reset, the default value is 15 (decimal) which corresponds to a OVR threshold of 0.56dB below fullscale (20 x log(15/16)).

This OVR threshold is applicable to both channels.

Default 1111



Register Address		Register Data														
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
3	0	DC Offset Coff ChA	0	0	1	0	1	1	0	0	0	1	1	0	0	0

D14 DC Offset Corr ChA Starts DC offset correction loop for ChA

Default 1

Starts offset correction loop for ChADC offset correction loop is cleared

D11, 9, 8, 4, 3 Must be set to 1 for maximum performance

Default 1



Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
Е		Sync Select														

D15-D2 Sync Select Sync selection for the clock generator block (also

Default 1010 1010 need to see address 0x0F)

1010 10

0000 0000 0000 00 Sync is disabled

0101 0101 0101 01 Sync is set to one shot (one time synchronization only)

1010 1010 1010 10 Sync is derived from SYNC input pins

1111 1111 111 not supported

Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
F		Sync	Select		0	0	0	0	0	\	/REF Se	el	0	0	0	0

D15-D12 Sync Select Sync selection for the clock generator block

Default 1010

0000 Sync is disabled

0101 Sync is set to one shot (one time synchronization only)

1010 Sync is derived from SYNC input pins

1111 not supported

D6-D4 VREF SEL Internal voltage reference selection

Default 000

000 1.0V 001 1.25V 010 0.9V 011 0.8V 100 1.15V

Others external reference

Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
1A	0	Start Auto Corr ChB	0	0	1	0	1	1	0	0	0	1	1	0	0	0

D14 Start Auto Corr ChB Starts DC offset and Gain correction loop for ChB

Default 1

0 Starts the DC offset and Gain correction loops for ChB

Clears DC offset correction value to 0 and Gain correction value to 1

D11, 9, 8, 4, 3 Must be set to 1 for maximum performance

Default 1



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Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
2B	0	0	0	0	0	0	0				Te	mp Sen	sor			

D8-D0 **Temp Sensor** Internal temperature sensor value – read only

Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
2C								Re	set							

D15-D0 Reset

Default 0000 This is a software reset to reset all SPI registers to their default value. Self

clears to 0.

1101001011110000

Perform software reset

Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
37			Sleep	Modes			0	0	0	0	0	0	0	0	0	0

D15-D14 Sleep Modes Sleep mode selection which is controlled by the ENABLE pin. Sleep modes are active when Default 00 ENABLE pin goes low. 000000 Complete shut down Wake up time 2.5 ms 100000 Stand-by mode Wake up time 100 µs 110000 Deep sleep mode Wake up time 20 µs 110101 Light sleep mode Wake up time 2  $\mu s$ 





Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
38		HP Mode 2									SYNC EN	LP Mode 1	0	0	0	0

D15-D7 HP Mode 2

Default 111111111

1 Set to 1 for normal operation

D6 BIAS EN Enables internal fuse bias voltages – can be disabled after

Default 1 power up to save power.

0 Internal bias powered

down

1 Internal bias enabled

D5 **SYNC EN** Enables the SYNC input buffer.

Default 1

0 SYNC input buffer

disabled

1 SYNC input bffer enabled

D4 LP Mode 1 Low power mode 1 to disable unused internal input buffer

Default 1 Internal input buffer

disabled

0

1 Internal input buffer

enabled

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Register Address								Re	gister	Data						
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
3A		LVDS Current Strength LVDS SW					rnal DS nation	0	0	0	0	DACLK EN	DBCLK EN	0	OVRA EN	OVRB EN

D15-D13	LVDS Current Strength Default 000	t	LVDS output current strength.
000	2 mA	100	3 mA
001	2.25 mA	101	3.25 mA
010	2.5 mA	110	3.5 mA
011	2.75 mA	111	3.75 mA
D12-D11	LVDS SW Default 01	LVDS	driver internal switch setting – correct range must be set for setting in D15-D13
01	2 mA to 2.75 r	mΑ	
11	3mA to 3.75m	Α	
D10-D9	Internal LVDS Termination Default 00	6	Internal termination
00	2 kΩ		
01	200 Ω		
10	200 Ω		
11	100 Ω		
D4	DACLK EN Default 1		Enable DACLK output buffer
0	DACLK output	buffer	powered down
1	DACLK output	t buffer	enabled
D3	<b>DBCLK EN</b> Default 1		Enable DBCLK output buffer
0	DBCLK output	t buffer	powered down
1	DBCLK output	buffer	enabled
D1	OVRA EN Default 1	Enabl	e OVRA output buffer
0	OVRA output	buffer p	powered down
1	OVRA output	buffer e	enabled
D0	OVRB EN Default 1	Enabl	e OVRB output buffer
0	OVRB output	buffer p	powered down
1	OVRB output	buffer e	enabled



Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
66							LVE	OS Outp	ut Bus A	EN						

D15-D10	LVDS Output Bus A EN Default FFFF	Individual LVDS output pin power down for channel A
0	Output is powered down	
1	Output is enabled	
D15	Pins N7, P7 (no connect pins	s) which are not used and should be powered down for power savings
D14	Pins N6, P6 (no connect pins	s) which are not used and should be powered down for power savings.
D13	SYNCOUTP/N (pins N5, P5)	
D12	Pins N4, P4 (no connect pins power savings	s) which are not used and should be powered down for
D11-D0	corresponds to DA11-D0	

Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
67							LVE	S Outp	ut Bus B	BEN						

D15-D10	LVDS Output Bus B EN Default FFFF	Individual LVDS output pin power down for channel B
0	Output is powered down	
1	Output is enabled	
D15	Pins G3, G4 (no connect pins	) which are not used and should be powered down for power savings
D14	Pins F3, F4 (no connect pins)	which are not used and should be powered down for power savings.
D13	SYNCOUTP/N (pins F1, F2)	
D12	Pins E3, E4 (no connect pins) power savings	which are not used and should be powered down for
D11-D0	corresponds to DB11-DB0	

### **REVISION HISTORY**

# Changes from Original (March 2013) to Revision APage• Changed D13 in Register 66 From: SYNCOUTP/N (pins F1, F2) To: SYNCOUTP/N (pins N5, P5)36• Changed D12 in Register 66 From: "Pins E3, E4..." To: "Pins N4, P4..."36• Changed D11-D10 - corresponds to DB11-DB0 in Register 66 To: D11-D0 -corresponds to DA11-D036• Changed D11-D10 - corresponds to DB11-DB0 in Register 67 To: D11-D0 -corresponds to DB11-DB036



# PACKAGE OPTION ADDENDUM

16-Aug-2013

### **PACKAGING INFORMATION**

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Orderable Device	Status	Package Type	U	Pins	U	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)		(3)		(4/5)	
ADS5407IZAY	ACTIVE	NFBGA	ZAY	196	160	Green (RoHS & no Sb/Br)	SNAGCU	Level-3-260C-168 HR	-40 to 85	ADS5407I	Samples
ADS5407IZAYR	ACTIVE	NFBGA	ZAY	196	1000	Green (RoHS & no Sb/Br)	SNAGCU	Level-3-260C-168 HR	-40 to 85	ADS5407I	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

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# PACKAGE MATERIALS INFORMATION

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# TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

# QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



# \*All dimensions are nominal

Device	Package Type	Package Drawing			Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ADS5407IZAYR	NFBGA	ZAY	196	1000	330.0	24.4	12.3	12.3	2.3	16.0	24.0	Q1

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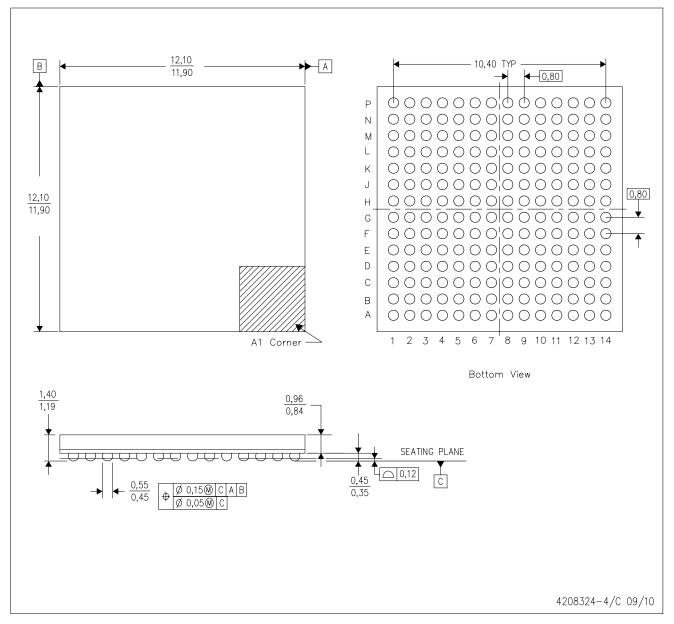


### \*All dimensions are nominal

ĺ	Device Package Type		Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
	ADS5407IZAYR	NFBGA	ZAY	196	1000	336.6	336.6	31.8	

# ZAY (S-PBGA-N196)

# PLASTIC BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. This is a Pb-free solder ball design.



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